


<b>Search Notes</b> 		<b>Application No.</b> 10/044,686		<b>Applicant(s)</b> SAKAI ET AL.	
		<b>Examiner</b> Felisa C. Hiteshew		<b>Art Unit</b> 1765	

SEARCHED			
Class	Subclass	Date	Examiner
117	84	10/9/2003	F.H.
117	104	10/9/2003	F.H.
117	937	10/9/2003	F.H.
Updated Search			F.H.
		3/13/04	
Updated Search			F.H.
		2/8/05	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
STN (hcaplus, inspec, japio, uspatall) s (GaN or gallium(w)nitride) s (nitride)(8a)(crystal#) s (cut?(8a)substrate#)	2/8/05	F.H.
s (front)(8a)(surface#) s (back?)(8a)(surface#) s (cut? or grind?)(8a)(substrate#) s (sapphire) s (electrode#)		